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INNOVATIVE BYPASS CIRCUIT FOR CIRCUIT TESTING AND MODIFICATION

ABSTRACT

An integrated circuit module is designed with bypass switchs (140) in critical places to route signals around specific circuit blocks (110, 120, 130), eg an automatic gain control (AGC) system (100) and an anti-aliasing filter. If there had been significant problems with either block (110, 120, 130), it can be bypassed and tests of the remaining circuits are possible. This allows all circuits in the module to be tested in the initial pass, reducing the risk of needing a third pass after the known problems were fixed in the second pass. Additionally, the bypass circuits (140) are useful at module production test and for diagnostics in the final product.

Fig. 1



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